

Wafer Test Board

Wafer Test Board makes easy connection with the wafer prober in the wafer level test



Testing Frequency	Max. 1GHz
Parallel Measurement	128DUT (x 18bit)
	256DUT (x 9bit)



Address : 58-6, D.I Building, Nonhyun-Dong, Gangnam-Gu, Seoul, Korea

Phone : 82-2-3416-1856

Fax : 82-2-545-5791

E-mail : jypark@di.co.kr

www.di.co.kr

© 2012 DI Corporation All Right Reserved.